

Uncertainty quantification of beam parameters in an LIA inferred from Bayesian analysis of solenoid scans

M.A. Jaworski¹, D.C. Moir¹, S. Szustkowski¹ Los Alamos National Laboratory

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Outline

Why is uncertainty quantification worth the effort?

- Old and new tools used to assess beam parameters in DARHT via the beam envelope equation
- Results from a Bayesian analysis of a solenoid scan





Measurements are not worth much without an uncertainty

- Distinguishing between models/theories requires precision measurements (i.e. need uncertainties to be quantified)
- Distinguishing measurement methods depends on uncertainties
 - Solenoid-scan method (~10-20 shots)[1]
 - Emittance mask methods (~1 shot?)[2]
 - PIC analysis of solenoid scans (~10-20 shots)[3]
- Understanding machine variability depends on measurement precision
- Predictive tuning requires well-understood initial conditions

[1] e.g. A. Paul, NIM Phys Res. 1991. [2] S. Szustkowski, IPAC 2022. [3] A. Press, IPAC 2022.



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Beam envelope equation enables analysis and tuning of LIAs

- Beam radius evolution through focusing, acceleration, including space charge
- Various derivations either from beam moments¹ or paraxial equations²
- Use for LIA analysis developed to high degree in IDL-based xtr code³
- PIC comparisons with xtr show favorable results⁴

¹Lee and Cooper, Part. Accel. 7 (1976) 83. ²cf Reiser "Theory and Design…" 2008. and Humphries "Charged Particle Beams" 2002. ³Allison, LA-UR-01-6585 (2001) ⁴Ekdahl, et al., IEEE Trans. Plasma Sci. 45 (2017) 2962.



Actual LIAs require improvements beyond "textbook" envelope equation

- xtr and simpleEnvelope (new, python-based code) include more space-charge effects
- xtr developed w/ experimental validation; multi-person-year effort
- simpleEnvelope developing new features and undergoing codecode validation (initially)

Beam Physics Modeled	xtr	simpleEnvelope	Approximate Effect 0(1)		
Electrostatic neutralization	Yes	Yes			
Current neutralization	No	Yes	Ø(1)		
Foil focusing	Yes	Yes	Ø(1)		
Beam potential depression	Yes	Yes	Ø(0.1)		
Beam diamagnetism	Yes	No	Ø(0.01)		
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Solenoid scan at DARHT-1 injector provides experimental database for work

- Low energy, high-current beam
 - I_b=1626±3A
 - T=3.234±0.016MeV
- OTR measurements made on aluminized Kapton
 - Each image has marginal distribution at $θ_i$
 - RMS mean and std. dev. from N angle cuts
 - 24 cuts for each image
- Anode solenoid swept through excitations (53.73±0.1cm from cath.)



[1] S. Szustkowski, IPAC 2022. [2] DC Moir, LA-UR-21-21386

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Experimental parameters for this scan

- Beam energy cross-calibration yields 95% credible interval
 - This work demonstrates the importance of this measurement precision
- Current uncertainty estimated at 0.5%
- RMS beam radius uncertainty estimated from multiple angle cuts method
- Beam initial conditions are simulated from the cathode location



xtr solution method minimizes χ²-like figure-of-merit

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- xtr FOM sums normalized variances
 - R_{meas}: observations
 - R_t : model value for given R_0 , R_0 ', ϵ_N
- For normal distr., χ² is "interpretable" w.r.t. probability distribution[1]
- Xtr FOM similar to χ^2 , if
 - assuming $\sigma_{meas} \sim r_t$
 - Uncertainty characterized by FOM doublings (X% increase to 2x FOM)
 - $\chi^2 \text{ doubling is } large \text{ decrease in } probability of a normal dist.}$
- Xtr solution: R₀=1.381cm, R₀'=72.6mrad, ε_N=957 mm-mrad

[1] D.S. Sivia "Data Analysis: A Bayesian Tutorial" 2006.

FOM_{xtr} =
$$\left[\sum_{i=1}^{N} \frac{(r_{meas,i}/r_{t,i}-1)^2}{N}\right]^{1/2}$$

$$\chi^2 = \sum_{i=1}^{N} \left(\frac{r_{meas,i} - r_{t,i}}{\sigma_{meas,i}} \right)^2$$

$$N \cdot \text{FOM}_{\text{xtr}}^2 = \sum_{i=1}^N \frac{(r_{meas,i} - r_{t,i})^2}{r_{t,i}^2}$$



LIA parameter inference accomplished with nonlinear beam-envelope model

$$p(\mathbf{x}_0 | \mathbf{r}_{meas}, \mathbf{I}) = \frac{p(\mathbf{r}_{meas} | \mathbf{x}_0, \mathbf{I}) \times p(\mathbf{x}_0 | \mathbf{I}) \times p(\mathbf{I})}{p(\mathbf{r}_{meas}, \mathbf{I})}$$

$$\mathbf{x}_0 = (R_0, R'_0, \epsilon_N)$$
 $\mathbf{r}_{meas} = (r_{meas,i}, \sigma_{meas,i})$
 $\mathbf{I} = (T_i, I_{b,i}, z_{AM}, \ldots)$

$$p(\mathbf{r}_{meas}|\mathbf{x}_0, \mathbf{I}) \propto \exp\left[-\frac{1}{2} \left\|\frac{(f(\mathbf{x}_0, \mathbf{I}) - \mathbf{r}_{meas})}{\sigma_{meas}}\right\|^2\right]$$

$$\sigma_T, \sigma_I, \sigma_Z \cdots \sigma_\alpha \sim \mathcal{N}(0, \sigma_\alpha^2)$$
$$I_\alpha = \mu_{0,\alpha} + \sigma_\alpha$$

$$R_0, R'_0, \epsilon_N \sim \mathcal{U}(x_{\beta,min}, x_{\beta,max})$$

or

$$p(x_{\beta}, T) = p(x_{\beta}|T) \times p(T)$$

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$$x_{\beta}|T \sim \mathcal{N}\left(\mu_{x_{\beta}} + \frac{\Sigma_{x_{\beta},T}}{\Sigma_{T,T}}(T - \mu_{T}), \Sigma_{x_{\beta}x_{\beta}} - \frac{\Sigma_{x_{\beta},T} \cdot \Sigma_{T,x_{\beta}}}{\Sigma_{T,T}}\right)$$



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solution: $f(\mathbf{x}_0, \mathbf{I})$

distributed about beam-envelope

- σ_T varies with absolute instrument precision (~16keV)

Likelihood function assumed to be normally

- σ_z varies by reasonable estimate (1mm)
- σ_{l} varies as 0.5% precision
- Uninformative priors used to avoid biases
- Strong correlation with varying energy
 - Markov-Chain Monte Carlo (MCMC) solutions generally less efficient
 - Hierarchical model employed to break correlations
 - Sampled as conditional bivariate normal distributions
 - PYMC4 library used for sampling

Single energy simulation provides point-comparison to xtr results

- Perfectly known energy assumption provides comparison
- Xtr solution is OUTSIDE the uncertainty bounds
 - Beam diamagnetism not included in simpleEnvelope
 - Approx. 1% reduction strength (~2A)
 - FOM doubling me pessimistic given
- UQ demonstrates the ability to distinguish beam physics models

.15111			mm-mrad		0.1	2 -	1.95 mrad
ctior	n in solenoid	0.00 1080 1100	0 1120 1140 emitN [mm-mrac	1160 11 j]	80 0.	0⊥ <u> </u>	1 72 73 Rp0 [mrad]
etric the	in xtr is data quality			2.00 - 1.75 - E 1.50 -	A. Marine		xtr soln. (in xtr) xtr soln. (in simpleEnv simpleEnvelope soln. Measured
	simple- Envelope	xtr	Units	- 1.25 W W W 1.00 -		A A	Beam Diamagnetism
R	1.432±0.003	1.38±0.02	cm	₩ 0.75			
R ₀	' 72.5±0.5	72.6±3.5	mrad	0.50	185 3	L90	195 200 205
٤ _N	1132±14	957±96	mm-mrad				Magnet Current [A]
	ΙA	-UR-22-2	8061				• LOS A

Beam Emittance

55

0.03

0.02

0.01

xtr

Probability [-]

Beam Radius

110 µm

R0 [cm]

Beam Divergence

1.435

1.430

Total Draws Normal Dist.

μ ± 99% C.I ± 95% C.I.

1.440

Total Draws

Normal Dist

μ ± 99% C.I.

± 95% C.I.

74

210

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amos BORATORY

215

150

Probability [-]

50 -

1.0

0.8

Ξ

Probability |

Total Draws

Normal Dist

μ ± 99% C.I.

± 95% C.I.

1.420

xtr

1.425

Finite, absolute precision of energy measurement affects uncertainties

- Gap voltage monitored with e-dot
 - Recently recalibrated against electron spectrometer [1]
 - Uncertainty in absolute calibration is ±17keV at 3.4MeV (~0.5%)
 - Pulse-to-pulse variability only $\sim 0.2\%$
- **Energy variation** expands uncertainty
 - 1% energy change leads to 6.5% R_0 variation
 - Strongly affects accelerator transport and matching



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150

Probability [-]

50

1.420

Results indicate applicability for further parameter and machine inferences

- New experiments and measurements are being devised to better constrain lab kinetic energy, T
- Basic methodology can be extended to include
 - Magnet misalignments, positioning errors
 - Charge and current neutralization effects
 - Further space-charge and beam distribution effects
- UQ approach will continue to depend on high-quality data for credible inferences and constraints

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Summary

- Rigorous approach to uncertainty enables scientific discovery through model differentiation and efficient data use
- Comparison of MAP-like solution in xtr with Bayesian simpleEnvelope allows model differentiation for a ~1% effects
 - Solenoid scan method strongly constrains solutions for a given lab kinetic energy value
 - xtr uncertainty estimates are pessimistic w.r.t. data quality
- Absolute energy variation greatly expands uncertainty of beam inlet radius, but basic methodology has potential in further studies

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Backup





Mix of proven and development methods are used to characterize LIAs like DARHT

- Beam envelope models used for tuning require beam radius, convergence, and emittance
- Long-established method is the solenoid scan (~10-20 shots)[1]
- Developing interpretation of emittance-mask methods (a.k.a. pepper-pots) (~1 shot?)[2]
- Also examining the use of full 2D and 3D PIC simulations for regular solenoid scan interpretation (~10-20 shots)[3]
- UQ is necessary for method comparisons

[1] e.g. A. Paul, NIM Phys Res. 1991. [2] S. Szustkowski, IPAC 2022. [3] A. Press, IPAC 2022.



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Understanding the sources of machine variability can also come from UQ studies

- DARHT and similar light sources must perform reliably and repeatably
- Measurement precision (i.e. uncertainty) determines the degree to which variations can be observed ("Is it out of the noise floor?")
- Separating instrumental "noise" from real variations in machine parameters often requires understanding entire system (or facility)



Bayesian analysis works by deriving probabilities of parameters given the observables $p(\mathbf{x}_0, \mathbf{r}_{meas}, \mathbf{I}) = p(\mathbf{x}_0 | \mathbf{r}_{meas}, \mathbf{I}) \times p(\mathbf{r}_{meas}, \mathbf{I})$

- Bayes rule derived from manipulating joint distribution
- Solution of probability distribution gives uncertainty bounds automatically
- Practical problems do not assume functional form – not tractable analytically
- Markov-Chain Monte Carlo (MCMC) provides a numerical solution for the posterior distribution

$$\begin{array}{ll} \text{posterior} & \text{likelihood} & \text{prior(s)} \\ p(\mathbf{x}_0 | \mathbf{r}_{meas}, \mathbf{I}) = \frac{p(\mathbf{r}_{meas} | \mathbf{x}_0, \mathbf{I}) \times p(\mathbf{x}_0 | \mathbf{I}) \times p(\mathbf{I})}{p(\mathbf{r}_{meas}, \mathbf{I})} \end{array}$$

$$p(\mathbf{r}_{meas}, \mathbf{I}) = \int_{-\infty}^{\infty} p(\mathbf{x}_0, \mathbf{r}_{meas}, \mathbf{I}) d\mathbf{x}_0$$
$$\mathbf{x}_0 = (R_0, R'_0, \epsilon_N)$$
$$\mathbf{I} = (T_i, I_{b,i}, z_{AM}, \ldots)$$
$$\mathbf{r}_{meas} = (r_{meas,i}, \sigma_{meas,i})$$
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